


PATENT

**IN THE UNITED STATES PATENT
AND TRADEMARK OFFICE**

Applicants: Fracheboud et al.)	"EXPRESS MAIL" mailing label No.
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Examiner: To be assigned)	Application, P.O. Box 1450, Alexandria, VA
)	22313-1450
)	
)	Richard Zimmermann

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
Box Patent Application
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:


Submitted herewith for consideration by the examiner are copies of the documents
identified on the attached Form PTO-1449.

U.S. 6,453,566 is the U.S. counterpart to EPO 1 113 191 A2.

Entry and consideration of the submitted documents are solicited.

Respectfully submitted,

MARSHALL, GERSTEIN & BORUN LLP

By: 
James P. Zeller
Reg. No. 28,491
Attorneys for Applicants

September 15, 2003

6300 Sears Tower
233 South Wacker Drive
Chicago, Illinois 60606-6357
(312) 474-6300

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INFORMATION DISCLOSURE STATEMENT		Applicant Fracheboud et al.	
		Filing Date 9/15/03	Group

U.S. PATENT DOCUMENTS							
*Examiner Initials		Document Number	Issue Date	Name	Class	Subclass	Filing Date if Appropriate
		3,869,799	03/11/75	Neuer et al.	33	174 L	
		4,964,223	10/23/90	Linder et al.	33	556	
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FOREIGN PATENT DOCUMENTS								
*Examiner Initials		Document Number	Publication Date	Country	Class	Subclass	Translation	
							Yes	No
		102 744 B1	03/14/84	EPO				
		1 013 949 A1	06/28/00	EPO			Abstract only	
		1 113 191 A2	07/04/01	EPO			Abstract only	
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)		
		"Accuracy Limitations of Fast Mechanical Probing", van Vliet et al., Eindhoven University of Technology, Section Precision Engineering, Eindhoven, The Netherlands, January 8, 1996, pp. 483 - 487
		"Development of a 2D Probing System With Nanometer Resolution", Pril et al., Eindhoven University of Technology, Eindhoven, The Netherlands, American Society for Precision Engineering, Proceedings Volume 16, 1997, pp. 438-442
		"Design for a Compact High-Accuracy CMM", Peggs et al., Center for Length Metrology, National Physical Laboratory, Teddington, Middlesex, UK, January 8, 1999, pp. 417-420
		European Search Report in EP 02 020 887.2 dated March 17, 2003

Examiner	Date Considered
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>	